

IGBT - Field Stop II NGTB25N120FL2WG

This Insulated Gate Bipolar Transistor (IGBT) features a robust and cost effective Field Stop II Trench construction, and provides superior performance in demanding switching applications, offering both low on state voltage and minimal switching loss. The IGBT is well suited for UPS and solar applications. Incorporated into the device is a soft and fast co–packaged free wheeling diode with a low forward voltage.

Features

- Extremely Efficient Trench with Field Stop Technology
- $T_{Jmax} = 175^{\circ}C$
- Soft Fast Reverse Recovery Diode
- Optimized for High Speed Switching
- 10 µs Short Circuit Capability
- These are Pb-Free Devices

Typical Applications

- Solar Inverter
- Uninterruptible Power Inverter Supplies (UPS)
- Welding

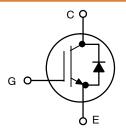
ABSOLUTE MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-emitter Voltage	V _{CES}	1200	V
Collector Current @ T _C = 25°C @ T _C = 100°C	lc	50 25	Α
Pulsed Collector Current, T _{pulse} Limited by T _{Jmax}	I _{CM}	100	Α
Diode Forward Current @ T _C = 25°C @ T _C = 100°C	I _F	50 25	Α
Diode Pulsed Current, T _{pulse} Limited by T _{Jmax}	I _{FM}	100	Α
Gate-emitter Voltage Transient Gate-emitter Voltage ($T_{pulse} = 5 \mu s, D < 0.10$)	V _{GE}	±20 ±30	V
Power Dissipation @ T _C = 25°C @ T _C = 100°C	P _D	385 192	W
Short Circuit Withstand Time V_{GE} = 15 V, V_{CE} = 500 V, $T_{J} \le 150^{\circ}C$	T _{SC}	10	μS
Operating Junction Temperature Range	TJ	–55 to +175	°C
Storage Temperature Range	T _{stg}	-55 to +175	°C
Lead temperature for soldering, 1/8" from case for 5 seconds	T _{SLD}	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

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25 A, 1200 V V_{CEsat} = 2.0 V E_{off} = 0.60 mJ





MARKING DIAGRAM



25N120FL2 = Specific Device Code

A = Assembly Location

Y = Year
WW = Work Week
G = Pb-Free Package

ORDERING INFORMATION

Device	Package	Shipping
NGTB25N120FL2WG	TO-247 (Pb-Free)	30 Units / Rail

THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal resistance junction-to-case, for IGBT	$R_{ heta JC}$	0.39	°C/W
Thermal resistance junction-to-case, for Diode	$R_{ heta JC}$	0.63	°C/W
Thermal resistance junction-to-ambient	$R_{\theta JA}$	40	°C/W

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Parameter Test Conditions		Min	Тур	Max	Unit
STATIC CHARACTERISTIC	•			-		
Collector-emitter breakdown voltage, gate-emitter short-circuited	$V_{GE} = 0 \text{ V}, I_{C} = 500 \mu\text{A}$	V _{(BR)CES}	1200	_	_	V
Collector-emitter saturation voltage	V _{GE} = 15 V, I _C = 25 A V _{GE} = 15 V, I _C = 25 A, T _J = 175°C	V _{CEsat}	- -	2.00 2.40	2.40 -	V
Gate-emitter threshold voltage	$V_{GE} = V_{CE}$, $I_C = 400 \mu A$	V _{GE(th)}	4.5	5.5	6.5	V
Collector-emitter cut-off current, gate- emitter short-circuited	V _{GE} = 0 V, V _{CE} = 1200 V V _{GE} = 0 V, V _{CE} = 1200 V, T _{J =} 175°C	I _{CES}	- -	_ 2.5	0.4 -	mA
Gate leakage current, collector-emitter short-circuited	V _{GE} = 20 V , V _{CE} = 0 V	I _{GES}	-	_	200	nA
DYNAMIC CHARACTERISTIC				•		
Input capacitance		C _{ies}	-	4420	_	pF
Output capacitance	V _{CE} = 20 V, V _{GE} = 0 V, f = 1 MHz	C _{oes}	-	151	_	
Reverse transfer capacitance		C _{res}	-	81	_	
Gate charge total		Qg	-	178	_	nC
Gate to emitter charge	V _{CE} = 600 V, I _C = 25 A, V _{GE} = 15 V	Q _{ge}	-	39	_	
Gate to collector charge		Q _{gc}	-	83	_	
SWITCHING CHARACTERISTIC, INDUC	TIVE LOAD					
Turn-on delay time		t _{d(on)}	-	87	_	ns
Rise time		t _r	-	28	_	
Turn-off delay time	T _J = 25°C	t _{d(off)}	-	179	_	
Fall time	$V_{CC} = 600 \text{ V, } I_{C} = 25 \text{ A}$ $R_{g} = 10 \Omega$	t _f	-	136	_	
Turn-on switching loss	V _{GE} = 0 V/ 15V	E _{on}	_	1.95	_	mJ
Turn-off switching loss	7	E _{off}	-	0.60	-	
Total switching loss	7	E _{ts}	-	2.55	-	
Turn-on delay time		t _{d(on)}	-	84	_	ns
Rise time	7	t _r	-	29	-	
Turn-off delay time	T _J = 150°C	t _{d(off)}	-	185	-	
Fall time	$V_{CC} = 600 \text{ V}, I_{C} = 25 \text{ A}$ $R_{q} = 10 \Omega$	t _f	-	245	-	
Turn-on switching loss	V _{GE} = 0 V/ 15V	E _{on}	-	2.39	-	mJ
Turn-off switching loss		E _{off}	-	1.26	_	1 !
Total switching loss		E _{ts}	-	3.65	-	
DIODE CHARACTERISTIC						
Forward voltage	V _{GE} = 0 V, I _F = 25 A V _{GE} = 0 V, I _F = 50 A, T _J = 175°C	V _F	- -	2.10 2.30	2.60 -	V
Reverse recovery time	T _J = 25°C	t _{rr}	-	154	_	ns
Reverse recovery charge	$I_F = 25 \text{ A}, V_R = 400 \text{ V}$ $di_F/dt = 200 \text{ A}/\mu\text{s}$	Q _{rr}	-	1.3	_	μς
Reverse recovery current	1	I _{rrm}	-	15	_	Α

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL CHARACTERISTICS

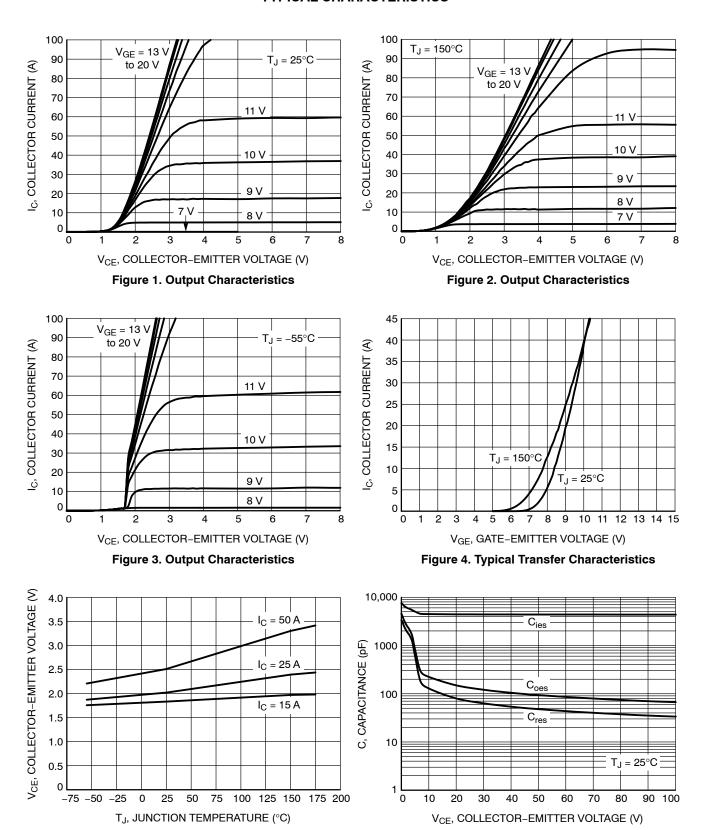


Figure 6. Typical Capacitance

Figure 5. V_{CE(sat)} vs. T_J

TYPICAL CHARACTERISTICS

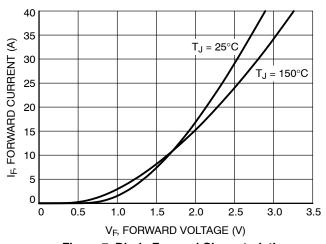


Figure 7. Diode Forward Characteristics

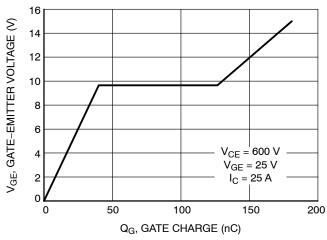


Figure 8. Typical Gate Charge

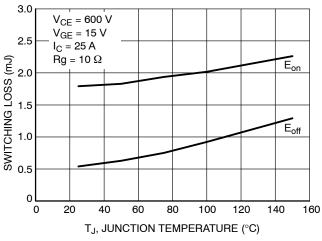


Figure 9. Switching Loss vs. Temperature

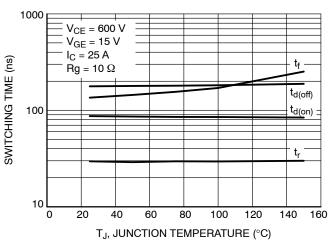


Figure 10. Switching Time vs. Temperature

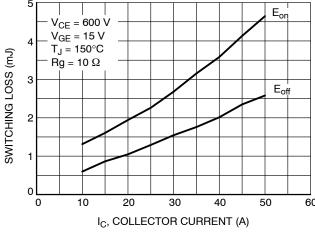


Figure 11. Switching Loss vs. I_C

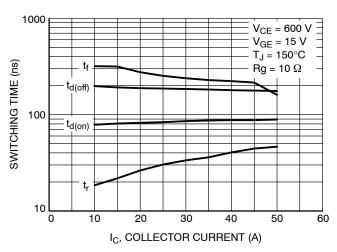


Figure 12. Switching Time vs. I_C

TYPICAL CHARACTERISTICS

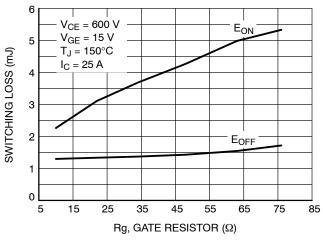


Figure 13. Switching Loss vs. Rg

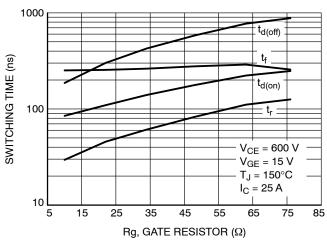


Figure 14. Switching Time vs. Rg

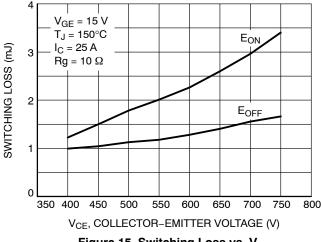


Figure 15. Switching Loss vs. V_{CE}

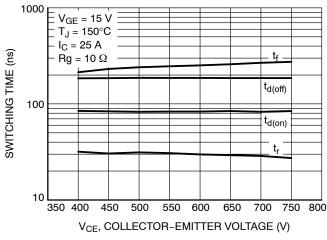


Figure 16. Switching Time vs. V_{CE}

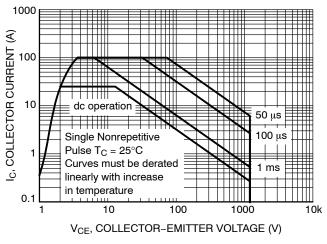


Figure 17. Safe Operating Area

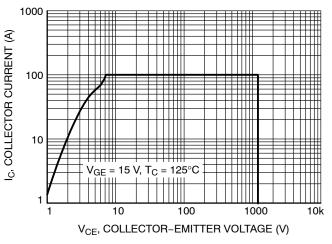


Figure 18. Reverse Bias Safe Operating Area

TYPICAL CHARACTERISTICS

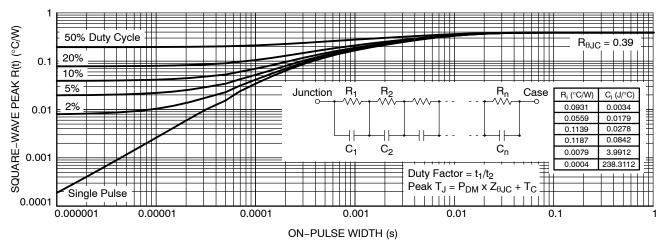


Figure 19. IGBT Die Self-heating Square-wave Duty Cycle Transient Thermal Response

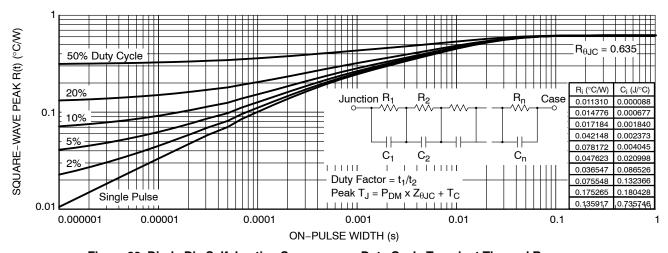


Figure 20. Diode Die Self-heating Square-wave Duty Cycle Transient Thermal Response

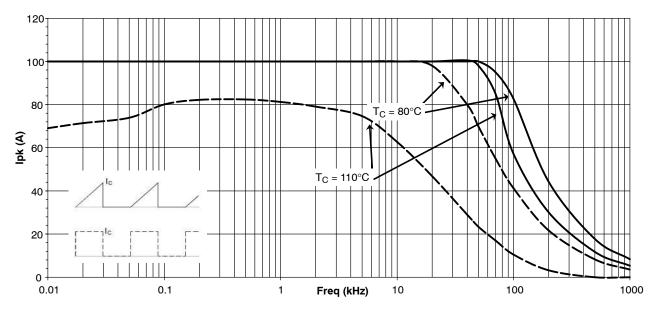


Figure 21. Collector Current vs. Switching Frequency

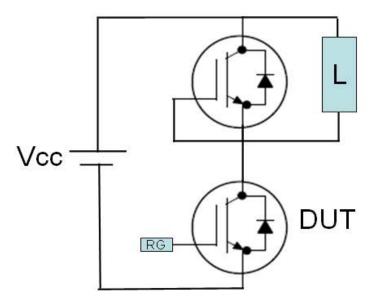


Figure 22. Test Circuit for Switching Characteristics

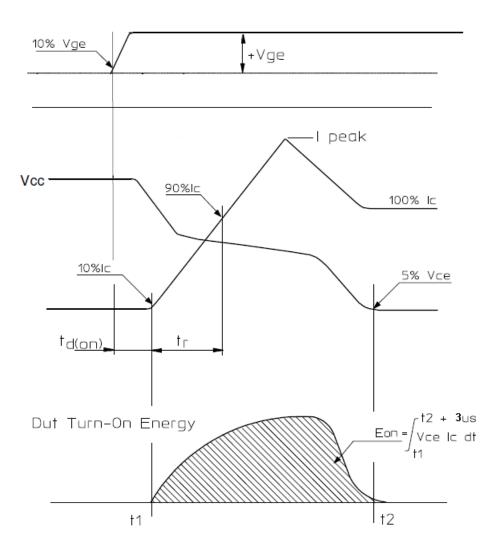


Figure 23. Definition of Turn On Waveform

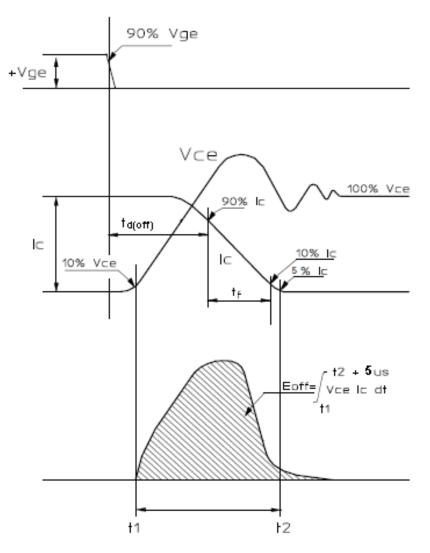
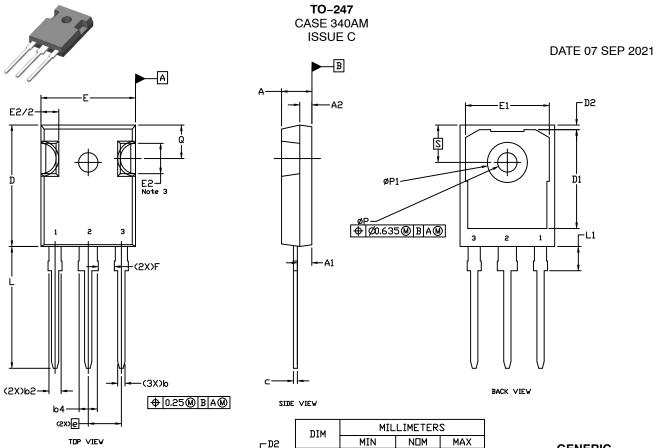


Figure 24. Definition of Turn Off Waveform



Α

A1

D1



NDTES:

- 1. DIMENSIONING AND TOLERANCE AS PER ASME Y14.5M, 2009.
- 2. ALL DIMENSION ARE IN MILLIMETERS.
- 3. SLOT REQUIRED, NOTCH MAY BE ROUNDED.
- 4. OPTIONAL BACK SIDE HEATSINK SHAPE.
- 5. DIMENSIONS ARE EXCLUSIVE OF BURRS AND MOLD FLASH.
 DIMENSIONS D AND E ARE MEASURED AT THE OUTERMOST EXTREME
 OF THE PLASTIC BODY.
- 6. DIMENSIONS AT TO BE MEASURED IN THE REGION DEFINED BY L1.
- 7. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

A2	1.80	2.00	2.20	
b	1.07	1.20	1.33	
b2	1.65	2.12	2.35	
b4	2.60	3.12	3.40	
C	0.45	0.60	0.75	
D	20.80	21.00	21.34	
D1	16.30			
D2	0.75			
Ε	15.50	16.00	16.25	
E1	13.80			
E2	4.32	4.90	5.49	
е	5.45 BSC			
F	2.655			

4.70

2.20

5.30

2.60

5.00

2.40

F	2.655			
L	19.80	20.00	20.80	
L1	3.81	4.20	4.35	
Р	3.55	3.60	3.65	
P1	6.60			
Q	5.40	6.00	6.20	
9	6.15 RSC			

GENERIC MARKING DIAGRAMS*





XXXX = Specific Device Code A = Assembly Location

Y = Year WW = Work Week G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

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